

In the two circuits shown below,  $V_B$  and  $R_B$  are adjusted such that  $I_{o1} = I_{o2} = I_o = 1 \text{ mA}$  at 300 K for the following nominal parameters:  $V_{CC} = 5 \text{ V}$ ,  $R_{L1} = R_{L2} = R_L = 1 \text{ k}\Omega$ , and  $I_s = 10 \text{ fA}$ ,  $\beta \rightarrow \infty$ ,  $V_A \rightarrow \infty$  for all transistors.

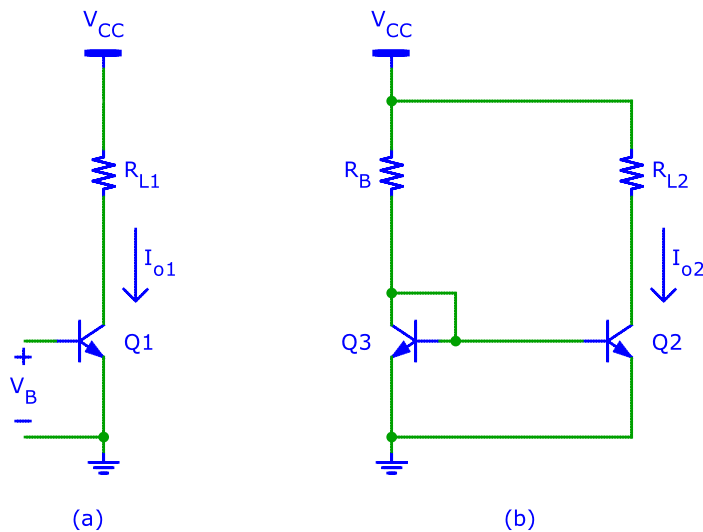
Now the temperature, supply voltage, load resistance and transistor parameters change as specified in the table below. Assuming  $V_B$  and  $R_B$  are kept constant, calculate the relative change of the currents  $I_{o1}$  and  $I_{o2}$  from their nominal value,  $I_o = 1 \text{ mA}$ . No entry in the table means “no change”.

|    | $T$   | $V_{CC}$ | $R_L$        | $I_s$ at 300K | $\beta$ | $V_A$ | $\frac{I_{o1}}{I_o} - 1$ [%] | $\frac{I_{o2}}{I_o} - 1$ [%] |
|----|-------|----------|--------------|---------------|---------|-------|------------------------------|------------------------------|
| a) |       |          |              |               |         |       | 0 %                          | 0 %                          |
| b) |       |          | 2 k $\Omega$ |               |         |       | 0 %                          | 0 %                          |
| c) |       | 6 V      |              |               |         |       | 0 %                          | 23 %                         |
| d) | 240 K |          |              |               |         |       | big decrease                 | little change!               |
| e) | 360 K |          |              |               |         |       | big increase*                | little change!               |
| f) |       |          |              | 20 fA         |         |       | 100 %                        | 0 %                          |
| g) |       |          |              |               | 50      |       | 0 %                          | -4 %                         |
| h) |       |          |              |               |         | 50 V  | 6.6 %                        | 6.6 %                        |

For each case, give a brief explanation what’s going on and how this is relevant for circuit design.

This circuit (especially the one on the right) is a core building block used in many more complicated circuits (operational amplifier, A/D converters, etc.). You will use it frequently in your designs and recognizing it will help you understand circuit operations without resorting to long calculations.

Note: specify answers to 5 % accuracy except cases d) and e) where its sufficient to specify the direction and order-of-magnitude of the change. Keeping this in mind lets you avoid lots of senseless nonlinear equation solving.



Comments:

b) No change. Q1 and Q2 act as (ideal, since  $V_A \rightarrow \infty$ ) current sources:  $I_C$  is independent of  $V_{CE}$ , as long as the transistor is in the forward active region.

Check:  $V_{CE} = V_{cc} - 2 \text{ k}\Omega \times 1 \text{ mA} = 3 \text{ V} \gg V_{ce(sat)} \approx 200 \text{ mV}$ .

c) No change for circuit (a), same reason as case b).

In circuit (b) the current through  $R_B$  increases by  $\frac{6 \text{ V} - V_{BE(on)}}{5 \text{ V} - V_{BE(on)}} \approx 23 \%$ . This change is “mirrored” to Q2 since both have the same  $V_{BE}$ .

- d) In circuit (a), the lower temperature changes both  $I_s$  and  $V_t$ . The change of  $I_s$  dominates and causes the current to decrease significantly. The accurate value can be calculated from the full equation for  $I_s$  and modeling the temperature dependencies of all its parameters. Using a circuit simulator (SPICE) is a simpler alternative.  
In circuit (b) the current through  $R_B$  changes only slightly since  $V_{BE3(on)}$  increases by approximately 120 mV ( $dV_{BE(on)}/dT \approx -2 \text{ mV/K}$  for constant  $I_C$ ). Since that current is mirrored to Q2,  $I_{o2}$  remains almost constant. This is a significant advantage over circuit (a).
- e) Same arguments as in case d), except that now  $I_{o1}$  increases substantially. For  $\Delta T = 60 \text{ K}$  the increase is sufficient to bring Q1 into saturation, and then the current actually decreases, hinted in the solution by the \* qualifier.
- f) In this case, we design for  $I_s = 10 \text{ fA}$ , but then use a transistor with  $I_s = 20 \text{ fA}$ . The value of  $I_s$  is not well controlled—datasheets specify a range of values. Typical variations are  $\pm 20\%$ , the example here with  $+100\%$  is a bit excessive.  
In circuit (a) the current is proportional to  $I_s$  and therefore doubles. In circuit (b) the change is minimal since the current is set by  $R_B$ . Since  $V_{BE3}$  drops slightly (bigger transistor), we see a small increase of the voltage across  $R_B$  and corresponding increase in current, but the change is negligible.
- g) For circuit (a) we see absolutely no change since the base current is delivered from the source  $V_B$ .  
In circuit (b), the current through  $R_B$  is 4% larger than  $I_{C2}$  since it includes the base currents of Q2 and Q3, each 2% of the collector currents. Why do we get -4%? The current through  $R_B$  does not change (the voltage across it remains the same) but  $I_{C2}$  is now 4% less.
- h) If we designed the circuit for  $V_A \rightarrow \infty$  but then built it in the lab with real transistors with  $V_A = 50 \text{ V}$  we would see a small current increase due to the  $1 + V_{CE}/V_A$  factor in the equation for  $I_C$ . For  $V_{CE} \approx V_{CC} - 1 \text{ V} - 0.7 \text{ V}$  the increase is 6.6%.

Both circuits implement current sources. Circuit (b) with “replica biasing” (transistor Q3 replicates the current source Q2 and is used to set the value of  $V_{BE2}$ ) is preferable since it is much less sensitive to variations, especially of temperature.

Often emitter degeneration (placing a resistor in series with the emitters of Q2 and Q3) is also used to further use sensitivity. We will study emitter degeneration extensively.